•	Sear	en Ne	otes	

Application/Control No.	Applicant(s)/Patent under Reexamination
09/985,788	GLUCK ET AL.
Examiner	Art Unit
Liang-che Alex Wang	2155

SEARCHED			
Class	Subclass	Date	Examiner
709	217, 230, 231, 236, 245, 248	7/17/2006	LW
710	70	7/17/2006	LW
725	115	7/17/2006	LW
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		-	
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
updated EAST Search: USPAT, EPO, JPO, DERWENT, USPUB	· 7/17/2006	LW
consulted with Patrice Winder	7/17/2006	LW
backed search	7/17/2006	LW
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